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Recent Advances in Image Processing and Computer Vision

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Deadline for manuscript submissions:

31 May 2024

Message from the Guest Editors

Computer vision is a research topic that is actively studied/explored by researchers from various domains. Advancements in image processing methods have paved the way for novel computer vision algorithms. Advanced computer vision methods have enabled automation in surgical procedures in healthcare, the quality inspection of parts in industries etc. The objective of this Special Issue of *Electronics* is to represent the state-of-the-art research progress in image processing and computer vision methods and their application in various domains. We invite researchers to contribute their original and unique articles, as well as review articles. Topics include, but are not limited to, the following areas:

- Object detection;
- Semantic segmentation;
- Defect detection;
- Digital image enhancement;
- Advances in machine vision/computer vision;
- 3D imaging;
- Optical metrology;
- Fringe analysis;
- Applications of 3D imaging.











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Message from the Editor-in-Chief

Electronics is a multidisciplinary journal designed to appeal to a diverse audience of research scientists, practitioners, and developers in academia and industry. The journal is devoted to fast publication of latest technological breakthroughs, cutting-edge developments, and timely reviews of current and emerging technologies related to the broad field of electronics. Experimental and theoretical results are published as regular peer-reviewed articles or as articles within Special Issues guest-edited by leading experts in selected topics of interest.

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